

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

Page 1 of 3

PATENT NO. : 5,587,523
DATED : December 24, 1996
INVENTOR(S) : Pan S. Jung, Daphne R. Yaniv

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

On the title page, under item [56],

---In the "Other Publications" section, replace "Basett" with --Baselt--.

---In the "Other Publications" section, replace "Van der Worf" with --Van der Werf--.

---In the "Other Publications" section, replace "P.S. Jung, "Novel Stationary-Sample Atomic Force Microscope with Beam-Tracking Lens", Dec. 14, 1992." with --P.S. Jung et al., "Novel Stationary-Sample Atomic Force Microscope with Beam-Tracking Lens", Electronic Letters, vol. 19 No. 3, 4 Feb. 1993, pp. 264-265.--.

---In the "Other Publications" section, in the publication by Stephen A. Joyce, replace "Relaxtion" with --Relaxation--.

---In the "Other Publications" section, replace "Richard Sonnenfield" with --Richard Sonnenfeld--.

---In the "Other Publications" section, replace "P. Davidson" with --P. Davidsson--.

---In the "Other Publications" section, before "Paul West" delete "Exhibit B".

---In the "Other Publications" section, before "John Adam Kramer" delete "Exhibit A".